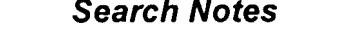


<b>Search Notes</b> 	Application/Control No.	Applicant(s)/Patent under Reexamination
	10/815,336	LIU, JAMES Z.
	Examiner Neil Turk	Art Unit 1743

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
(multi\$mode or multi\$4 or dual\$mode) same SAW and surface near wave EAST *see attached history	6/14/2007	NT
text EAST *see attached history	6/14/2007	NT
text EAST *see attached history	6/18/2007	NT

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner